

A tool-box strategy for layer-by-layer assembly of ultrathin hybrid films from graphene oxide and chromophores for organic electronics

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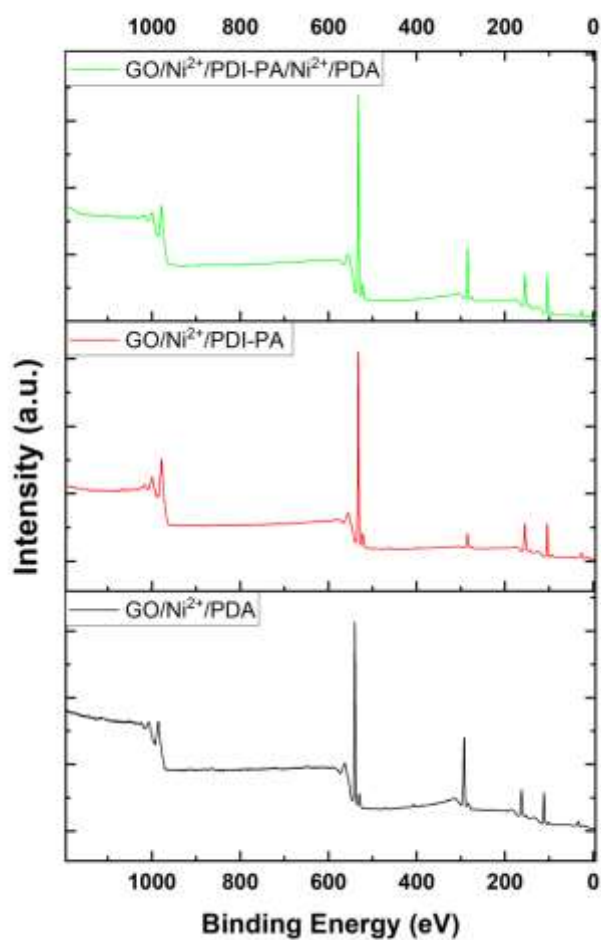


Figure S1. Overview XPS spectra of GO/Ni²⁺/PDA, GO/Ni²⁺/PDI-PA and GO/Ni²⁺/PDI-PA/Ni²⁺/PDA hybrid materials.

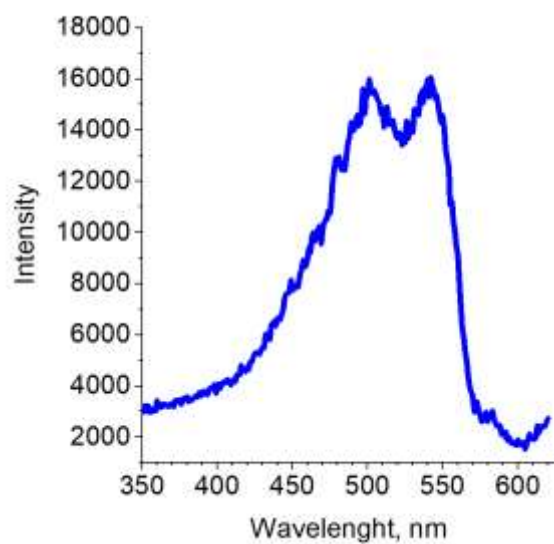


Figure S2. Excitation spectrum of PDA film, crystallized in the «red» form. $\lambda_{em}=640$ nm.

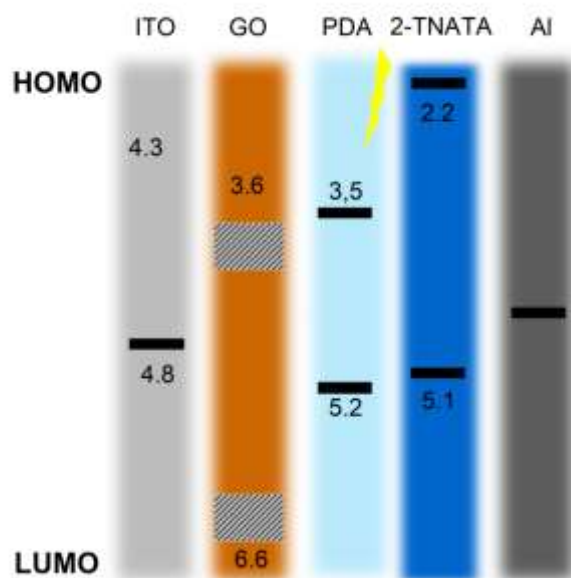


Figure S3. a) Schematically shown energy level diagram for the ITO/GO/PDA/2-TNATA/Al cell.

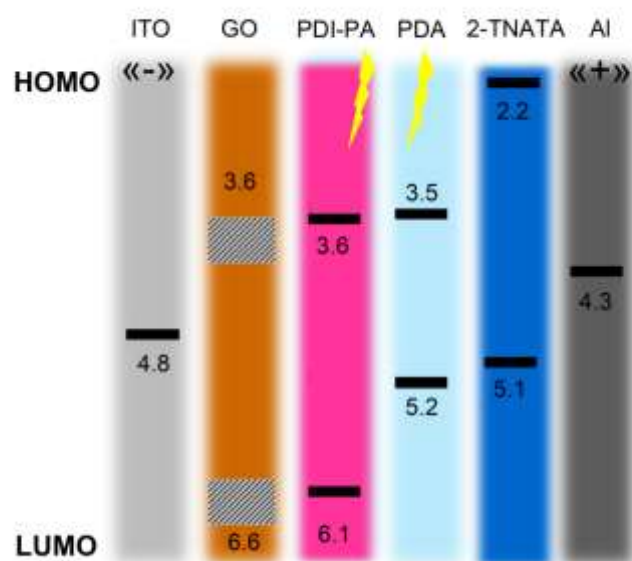


Figure S4. Schematically shown energy level diagram for the ITO/GO/Ni²⁺/PDI-PA/Ni²⁺/PDA/2-TNATA/Al cell.

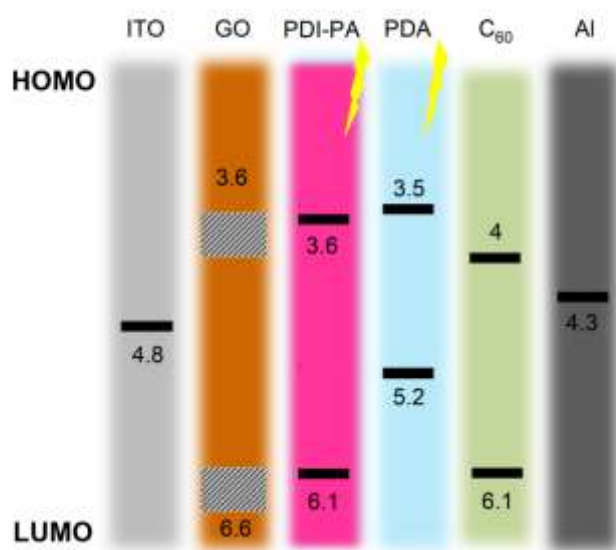


Figure S5. Schematically shown energy level diagram for the ITO/GO/Ni²⁺/PDI-PA/Ni²⁺/PDA/C₆₀/Al cell.

The HOMO and LUMO energies of GO, PDA, PDI-PA and work function of ITO, aluminum were taken from ¹⁻⁵. The values for 2-TNATA, C₆₀ and BCP provided by the manufacturer.

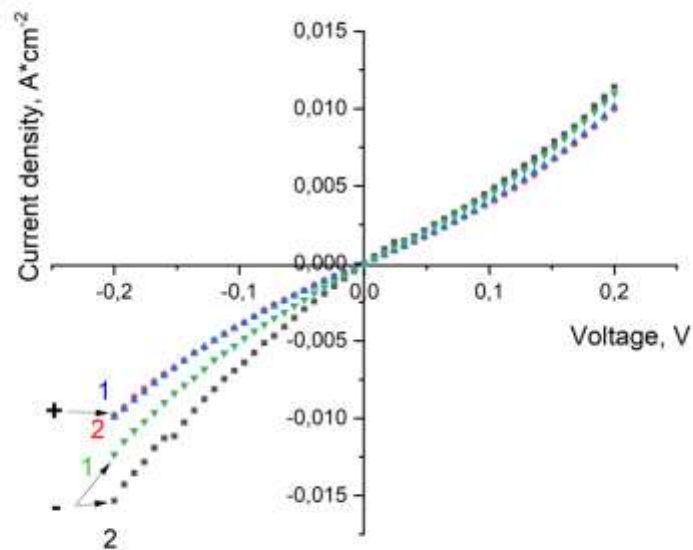


Figure S6. Current-voltage dependences of the ITO/GO/Ni²⁺/PDI-PA/PDA/2-TNATA/Al cell measured for (1) photocurrent and (2) dark current under positive and negative bias on ITO.

Ellipsometry allows to determine experimentally the real (ε_1) and imaginary parts (ε_2) of the (complex) dielectric permittivity, from which the dielectric permittivity of GO/Ni²⁺/PDI-PA/Ni²⁺/PDA/2-TNATA film was calculated:

$$\varepsilon = \varepsilon_1 + i \varepsilon_2.$$

Table S1. Values of ε_1 , ε_2 and dielectric permittivity, obtained by ellipsometry, and RMS error of optical modeling.

ε_1	2.768
ε_2	0.664
ε	2.847
RMSE	6.18×10^{-8}

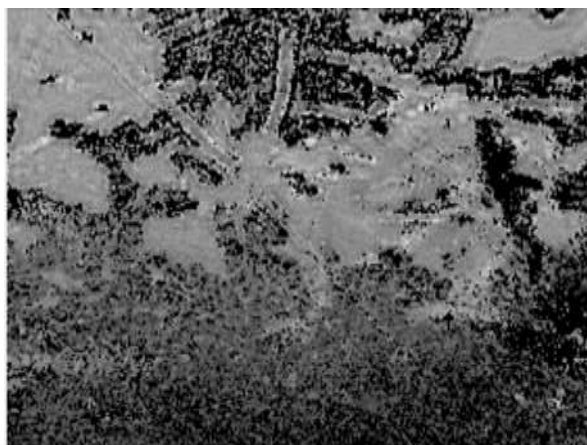


Figure S7. The area of the GO/Ni²⁺/PDI-PA/Ni²⁺/PDA/2-TNATA film from which the ellipsometric data were scanned.

References

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